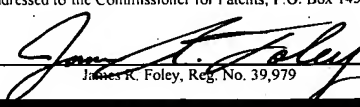


**PATENT**  
**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Serial No.: 10/696,320  
Inventor: Franklin Duan et al.  
Filed: October 29, 2003  
For: New Methodology to  
Measure Many More  
Transistors on the  
Same Test Area  
Examiner: Tung X. Nguyen  
Art Unit: 2829  
Atty. Ref.: 03-1169



Certificate of Mailing by "Express Mail"	
Mailing Label Number:	EV371846260US
Date of Deposit:	December 27, 2004
I hereby certify that this paper or fee is being deposited with the United States Postal Service "Express Mail Post Office Box Addressee" service under 35 CFR 1.10 on the date indicated above and is addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.	
 James R. Foley, Reg. No. 39,979	

**REQUEST FOR APPROVAL OF DRAWING AMENDMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Applicant submits the present Request along with a Response to an Office Action mailed November 17, 2004.

Please amend the drawings as follows:

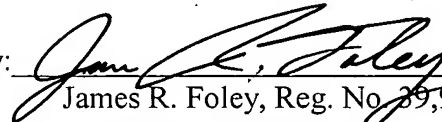
In Figure 1, please add the legend -- Prior Art --.

In accordance with the Rules, a replacement drawing sheet identified in the top margin as "Replacement Sheet" is enclosed.

Respectfully submitted,

TREXLER, BUSHNELL, GIANGIORGI,  
BLACKSTONE & MARR,

Dated: December 27, 2004

By:   
James R. Foley, Reg. No. 39,979  
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